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Venayagamoorthy, G.K.; Sundepersadh, N.;

Neural Networks, 2000. IJCNN 2000, Proceedings of the IEEE-INNS-ENNS International Joint Conference on , Volume: 5 , 24-27 July 2000

Pages: 253 - 258 vol.5

IEEE CNF [PDF Full-Text (368 KB)] [Abstract]

2 A self-organizing map for clustering probabilistic models

Hollmen, J.; Tresp, V.; Simula, O.;

Artificial Neural Networks, 1999. ICANN 99. Ninth International Conference on (Conf. Publ. No. 470), Volume: 2, 7-10 Sept. 1999 Pages:946 - 951 vol.2

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